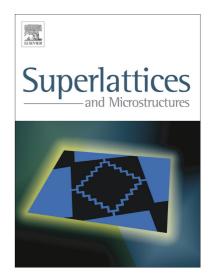
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Charge transport properties of Tl₂GaInSe₄ prepared by Bridgman technique

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Highlights

- 1. Tl₂GaInSe₄ crystal was prepared by a special design based on Bridgman technique.
- 2. The Hall coefficient indicates that the $Tl_2GaInSe_4$ has the p-type conductivity.
- 3. The acceptor level is located at 0.33 eV above the valance band of Tl_2 Ga In Se₄.

Abstract

Electronic transport properties of $Tl_2GaInSe_4$ prepared by Bridgman technique have been investigated by Dc electrical conductivity and Hall coefficient measurements. $Tl_2GaInSe_4$ crystal was prepared by a special design based on Bridgman technique.

The conductivity, Hall mobility and carrier concentration of the Tl₂GaInSe₄ were investigated as a function of temperature. The Hall coefficient indicates that the Tl₂GaInSe₄ has the p-type conductivity. The values of the electrical conductivity, Hall coefficient, and carrier concentration and Hall mobility at room temperature were $1.826 \times 10^{-5} \Omega^{-1} \text{cm}^{-1}$, $13.3 \times 10^8 \text{ cm}^3/\text{C}$ and $4.7 \times 10^9 \text{cm}^{-3}$ and $2.43 \times 10^4 \text{cm}^2 \text{ v}^{-1} \text{ s}^{-1}$, respectively. The analysis of the temperature dependent electrical conductivity and carrier concentration reveal that the acceptor level is located at 0.33 eV above the valance band of Tl₂Ga In Se₄.

The obtained electrical results indicate that the prepared Tl_2 Ga In Se₄ sample is a ptype semiconductor and it can be used for electronic device applications. Download English Version:

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